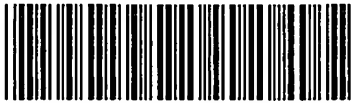


**Search Notes**

Application/Control No.

10/803,536

Examiner

Evan Dzierzynski

Applicant(s)/Patent under  
Reexamination

HAYASHI ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	465	8/9/2005	EPD
	466	8/9/2005	EPD
	505	8/9/2005	EPD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search help from Tom Sember	9/1/2005	EPD
STIC center search	9/1/2005	EPD
Search in east, see attachment	8/9/2005	EPD